



Low-Cost, High-Value Measurement System

	Range	mm
Starlite 200	X axis Y axis Z axis	200 150 150
Starlite 250	X axis Y axis Z axis	250 150 150
Starlite 300	X axis Y axis Z axis	300 300 150

Practicality
and performance
in a semi-automatic
system

The Starlite[™] benchtop video machines from Optical Gaging Products (OGP®) put the benefits of semi-automatic, non-contact video measurement within the reach of virtually any manufacturer. Starlite systems offer a long list of standard features —

- Intuitive metrology software. Gage-X[™] metrology software includes powerful functions for general purpose dimensional measurement with an easy-to-use graphic interface. Gage-X guides users through measurement routines with clear pictorial instructions using part model and destination symbols and icons. The exclusive CompuFocus[™] feature ensures repeatable focus results from user to user.
- **Superior optics.** The precise 6.5 to 1 motorized programmable zoom lens has an ample 70 mm working distance. Optional auxiliary lenses attach easily to expand the magnification range.
- **Mechanical integrity.** Starlites include precision mechanical bearing XYZ transports with 1.0 µm linear scales mounted to a stable granite base and column. Manual quick release XY motion controls allow rapid positioning while convenient adjustment knobs provide precise motion. Fine and coarse Z motion adjustment knobs simplify focusing.
- Image processing. Starlite with Gage-X features full field-of-view image processing with advanced edge detection algorithms designed for real world applications.



OGP**STARLITE**

Technical Specifications

200	250	300	■ Standard □ Option
			Measuring range (XYZ): 200 x 150 x 150 mm
			Measuring range (XYZ): 250 x 150 x 150 mm
			Measuring range (XYZ): 300 x 300 x 150 mm
			Measuring unit dimensions (approx LWH): 54 x 53 x 80 cm, 113 kg
			Measuring unit dimensions (approx LWH): 54 x 56 x 80 cm, 115 kg
			Measuring unit dimensions (approx LWH): 82 x 58 x 80 cm, 140 kg
			Shipping crate dimensions (approx LWH): 145 x 112 x 115 cm, 220 kg
			XYZ scale resolution: 1.0 µm
		•	Worktable: Anodized with fixture holes and removable stage glass, 20 kg load capacity (Starlite 200/250), 25 kg load capacity (Starlite 300)
			Zoom lens: Motorized, 6.5:1, field of view 8.89 – 1.78 mm, working distance 70 mm
			Accessories: 0.5x, 0.75x, 1.5x, and 2.0x lens options; 0.67x and 2.0x adapter tubes
			Camera: 1/2" format high resolution color CCD with 768 x 494 pixel array
			Illumination: Collimated profile, on-axis (TTL) surface and programmable ring light LED illuminators
			Image processing: 256 level grayscale processing with 10:1 sub-pixel resolution
			*On-screen magnification depends on monitor size. Figures shown are for a typical 20"LCD monitor.
			Power requirements: 100/110/220/240 vac, ± 5%, 50/60 Hz, 1 φ, 300 W
			Rated environment: 18-22° C, 30-80% humidity (non-condensing), vibration < 0.002g below 15 Hz
			Operating environment, safe operation: 5-40° C
			Metrology software: QVI Gage-X™
			Controller: Minimum configuration Pentium® processor @ 2.6 GHz, 1 GB RAM, 40 GB hard drive, 1.44 MB floppy drive, CD-ROM drive,
			parallel, serial, and USB 2.0 ports, on board 10/100 LAN
			Operating system: Microsoft® Windows™ XP
			Computer accessory package: 20"LCD monitor, keyboard, three button mouse
			Software: SmartReport® Plus, MeasureFit® Plus
			X,Y linear accuracy: E ₁ =(2.5 + 6L/1000) µm*
			X,Y linear accuracy: $E_1 = (3.5 + 6L/1000) \mu m^*$
			XY area accuracy: E_2 =(3.5 + 6L/1000) μ m*
			XY area accuracy: E_2 =(4.5 + 6L/1000) μ m*
			Z linear accuracy: $E_i = (7.0 + 8L/1000) \mu m^*$
			*Where L=measuring length in mm. Applies to thermally stable system in rated environment, maximum zoom lens setting, and evenly distributed 5 kg load. Depending on load distribution, accuracy at maximum rated load may be less than standard accuracy. XY axis artifact: QVI 25 intersection grid reticle at standard measuring plane. Z axis artifact: QVI step gage or master gage blocks.
			Warranty: One year
			Accessories: Calibration artifacts



Multisensor Metrology